

<b>Notice of References Cited</b>	Application/Control No. 10/646,491	Applicant(s)/Patent Under Reexamination TAKANO ET AL.	
	Examiner Pritham Prabhakher	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0025805 A1	02-2003	Yamagishi, Yoichi	348/222.1
*	B	US-2001/0020978 A1	09-2001	Matsui et al.	348/222
*	C	US-2001/0020979 A1	09-2001	Lathrop, George E.	348/222
*	D	US-6,512,540 B2	01-2003	Lathrop, George E.	348/222.1
*	E	US-2003/0048361 A1	03-2003	Safai, Mohammad A.	348/222.1
*	F	US-6,831,687 B1	12-2004	Suzuki, Masahiro	348/251
*	G	US-6,954,228 B1	10-2005	Acharya et al.	348/223.1
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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